ISO/TC22/SC3/WG3 N 2511

ISO/TC22/SC32 N

Date: 2015-09-10

7637-4

ISO/TC 22/SC32/WG 3

Secretariat: JSAE

Road Vehicles – Electrical disturbances by conduction and coupling – Part 4: Electrical transient conduction along shielded high voltage supply lines only

Véhicules routiers — Perturbations électriques par conduction et par couplage — Partie 2: Transmission des perturbations électriques par conduction uniquement le long des lignes d'alimentation

Document type: International Standard
Document subtype:
Document stage: (30) Committee
Document language: E

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Foreword

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The main task of technical committees is to prepare International Standards. Draft International Standards adopted by the technical committees are circulated to the member bodies for voting. Publication as an International Standard requires approval by at least 75 % of the member bodies casting a vote.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights.

ISO 7637-4 was prepared by Technical Committee ISO/TC 22, *Road vehicles*, Subcommittee SC 32, *Electrical and electronic equipment*.

ISO 7637 consists of the following parts, under the general title *Road vehicles — Electrical disturbances by conduction and coupling*:

— *Part 1: Definitions and general considerations*

— *Part 2: Electrical transient conduction along supply lines only*

— *Part 3: Electrical transient transmission by capacitive and inductive coupling via lines other than the supply lines.*

— *Part 4: Electrical transient conduction along shielded high voltage supply lines only*

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Road Vehicles – Electrical disturbance by conduction and coupling – Part 4: Electrical transient conduction along shielded high voltage supply lines only

1 Scope

This part of ISO 7637 specifies test methods and procedures to ensure the compatibility to conducted electrical transients of equipment installed on passenger cars and commercial vehicles fitted with electrical systems with voltages higher than 60 V_{DC} and lower than 1.000 V_{DC} and a power-supply isolated from the vehicle-body. It describes bench tests for both, injection and measurement of transients. It is applicable to all types of electrical independent driven, road vehicles (e. g. battery electrical vehicle [BEV] or hybrid electrical vehicle [HEV], plugin hybrid vehicle [PHEV]).

Failure mode severity classification for immunity to transients is given in annex A.

This document describes tests with internal pulses generated by the dc high voltage modules. Internal pulses:

- Voltage ripple (Pulse A);
- Pulsed sinusoidal disturbances (Pulse B);
- Low frequency sinusoidal disturbances (Pulse C).

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 7637-1: 2002, *Road vehicles -- Electrical disturbances from conduction and coupling -- Part 1: Definitions and general considerations*

ISO 16750-2: *Road vehicles -- Environmental conditions and testing for electrical and electronic equipment -- Part 2: Electrical loads*

3 Terms and definitions

For the purposes of this document, the terms and definitions given in ISO 7637-1 apply.

4 Test procedure

4.1 General

Methods for measuring the transient emission on shielded high voltage supply lines and test methods for the immunity of devices against transients are given. These tests, called "bench tests", are made in the laboratory.

The bench test methods will provide comparable and reproducible results between laboratories. They also give a test basis for the development of devices and systems and may be used during the production phase.

A bench test method for the evaluation of the immunity of a device against supply line transients may be performed by a test pulse generator; this may not cover all types of transients which can occur in a vehicle. Therefore, all described test pulses are typical pulses.

In special cases, it may be necessary to apply additional test pulses. However, some test pulses may be omitted, if a device, depending on its function or its connection is not influenced by comparable transients in the vehicle. It is part of the vehicle manufacturer's responsibility to define the test pulses required for a specific device.

Test pulse A is used to test equipment against transient voltages. The nearly rectangular shaped pulses include different harmonics and fast rise times. Due to the fact that the most energy is stored in the low frequency harmonics, pulse C can be used as a testing alternative for pulse A.
Test pulse B is used for testing high frequency oscillations, f.e. fast switching.

The DUT shall be operated under typical conditions which cause the maximum disturbance and sensitivity during the measurement. This is the worst case mode for every test and frequency step Conditions shall be agreed between vehicle manufacturer and supplier.

For all test setup adequate test equipment (e. g. connectors, cables, housings) shall be used.

4.2 Test temperature and test voltage

The ambient temperature during the test shall be (23 ± 5) °C.

The high voltage supply system can vary in a range from 60 V_{DC} up to 1.500 V_{DC}. The used voltage and its allowed tolerances of battery/generator in operation shall be agreed between vehicle manufacturer and supplier and shall be documented in the test plan.

4.3 Voltage transient emissions test along high voltage supply lines

This subclause defines a test procedure to evaluate automotive electrical and electronic high voltage components (DUT) for conducted emissions of transients along battery fed or switched high voltage supply lines. A device under test (DUT) which is considered as a potential source of conducted disturbances shall be tested according to the procedure described in this clause.

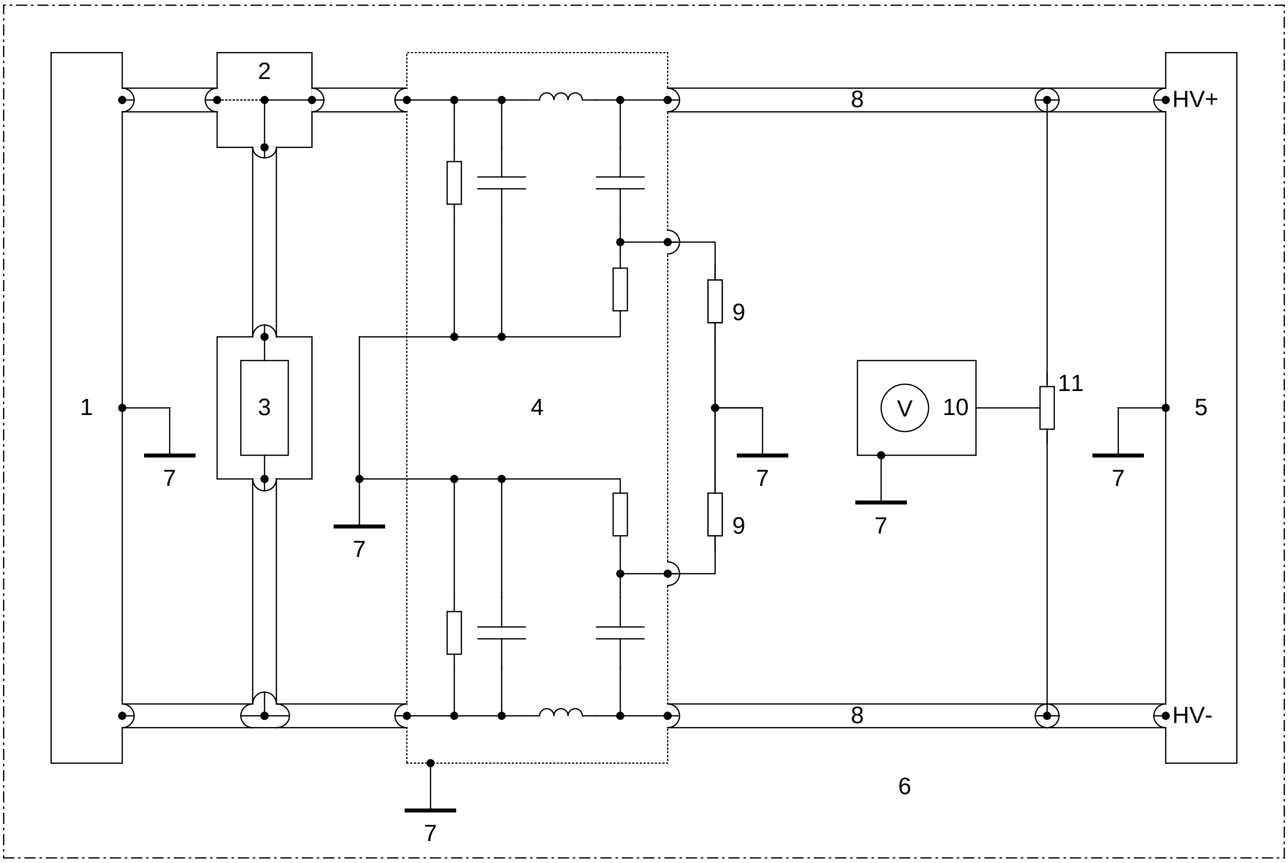
Care shall be taken to ensure that the surrounding electromagnetic environment does not interfere with the measurement set-up.

Voltage transients from the device under test (DUT), are measured using the shielded artificial network (for high voltages) to standardize the impedance loading on the DUT (see 5.1). The DUT is connected via the artificial network to the high voltage power supply (see 5.2) as given in figure 1.

If no other requirements are specified the DUT and all wiring connections between artificial network and DUT shall be spaced with a distance of $\left(50\ {}^{+10}_{\ \ 0}\right)$ mm above the metal ground plane.

The cable sizes shall be chosen in accordance with the real situation in the vehicle, i. e. the wiring shall be capable of handling the operating current of the device under test, and as agreed between vehicle manufacturer and supplier.

Supply voltage U_A and the disturbance voltage shall be measured close to the DUT-terminals using a voltage probe and oscilloscope or waveform acquisition equipment at the power supply terminals (see figure 1).



Key

1 shielded high voltage power supply
2 HV-Switch
3 load for high voltage battery (if necessary, see subclause 5.4)
4 shielded high voltage artificial network
5 DUT
6 ground plane
7 ground connection
8 high voltage supply line *)
9 50 Ohms termination
10 oscilloscope or equivalent
11 high voltage differential probe

Figure 1 – Transient emission test set-up to measure voltage ripple along high voltage supply lines

*) Length of the HV-cable depends from the routing in the vehicle, recommended sizes 200 mm +200/-0 mm or 1.700 mm + 300/ -0 mm (standard length) or length of the original HV-harness. The harness length shall be documented in the test plan. Ground connection of DUT shall be connected to ground plane with a cable original length and diameter according to the vehicle application.

Figure 1 shows the test setup for the measurement between HV+ and HV-. For measurement between HV+ and ground or HV- and ground the other terminal of the voltage probe has to be connected to ground.

Details to high voltage supply line length, ground connection and wiring shall be agreed between vehicle manufacturer and supplier.

The sampling rate and trigger level of the measurement instrumentation shall be selected to capture a waveform displaying the complete duration of the transient, and with sufficient resolution, to display the highest positive and negative portions of the transient.

Utilising the proper sampling rate and trigger level, the voltage amplitude shall be recorded by actuating the device under test according to the test plan. Other transient parameters, such as rise time, fall time, transient duration, etc. may also be recorded. Unless otherwise specified, ten waveform acquisitions are necessary. It is only necessary to report the waveforms with highest positive and negative amplitude (with their associated parameters). Measurements have to be taken in DUT worst case mode for each test and frequency.

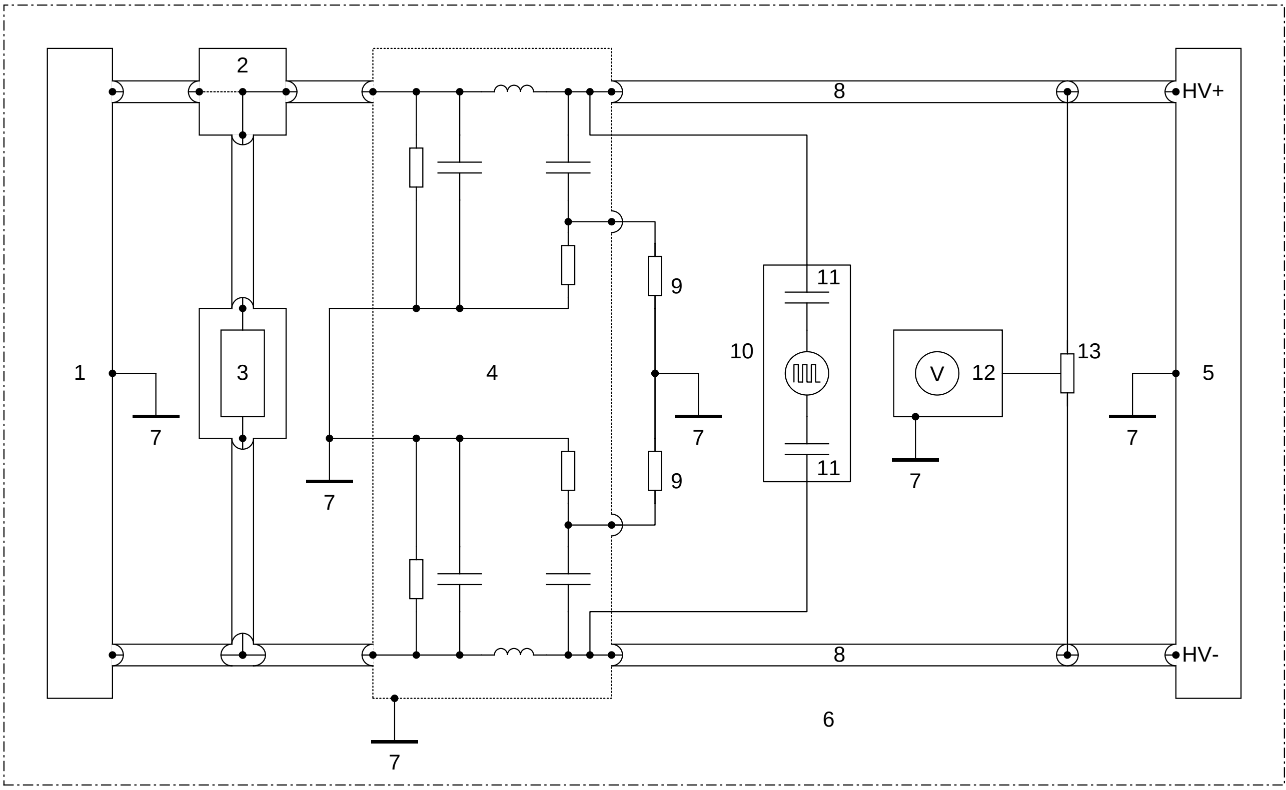
The measured transient shall be evaluated according to Annex C. All pertinent information and test results shall be reported. If required per test plan, include transient evaluation results with respect to the performance objective as specified in the test plan.

4.4 Transient immunity test along high voltage supply lines

Various types of transients appear on the high voltage supply lines, generated by the switching of various loads.

If not otherwise specified, all transient tests shall be performed between HV+ and HV- (line-to-line) and between HV+ respectively HV- and ground (line-to-ground). For voltage ripple, it is recommended to test also simultaneously HV+ and HV- to ground (lines-to-ground).

4.4.1 Voltage Ripple

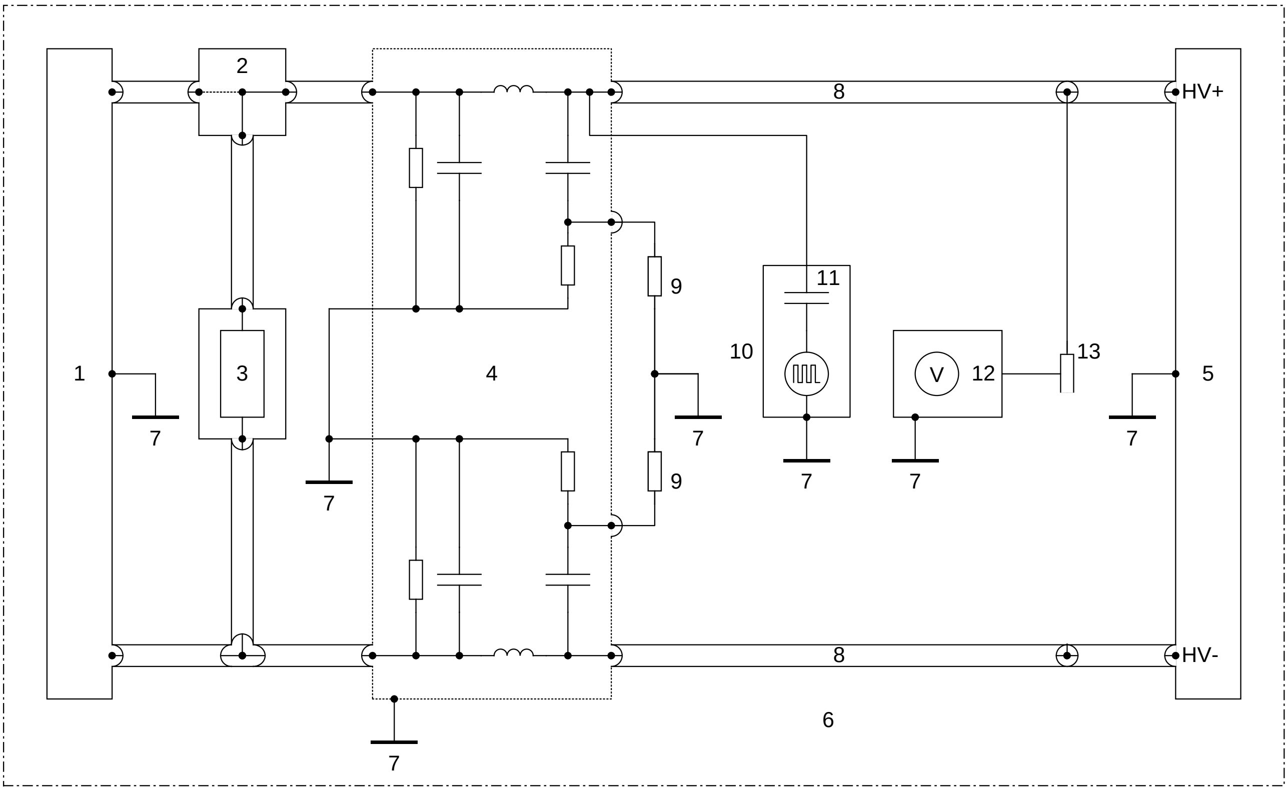


Key

1 shielded high voltage power supply
2 HV-Switch
3 load for high voltage battery (if necessary, see subclause 5.4)
4 shielded high voltage artificial network
5 DUT
6 ground plane
7 ground connection
8 high voltage supply line *)
9 50 Ohms termination
10 square wave generator
11 coupling capacitor
connection between generator output and HV lines as short as possible.
due to test setup a 2nd coupling capacitor at HV- side is optional
12 oscilloscope or equivalent
13 high voltage differential probe

Figure 2a – Transient immunity test set-up for voltage ripple (e. g. "line-to-line")

*) Length of the HV-cable depends from the routing in the vehicle, recommended sizes 200 mm +200/-0 mm or 1.700 mm + 300/ -0 mm (standard length) or length of the original HV-harness. The harness length has to be documented in the test plan.



Key

1 shielded high voltage power supply
2 HV-Switch
3 load for high voltage battery (if necessary, see subclause 5.4)
4 shielded high voltage artificial network
5 DUT
6 ground plane
7 ground connection
8 high voltage supply line *)
9 50 Ohms termination
10 square wave generator, both terminals shall be isolated to ground!
11 coupling capacitor
connection between generator output and HV lines as short as possible.
12 oscilloscope or equivalent
13 high voltage probe

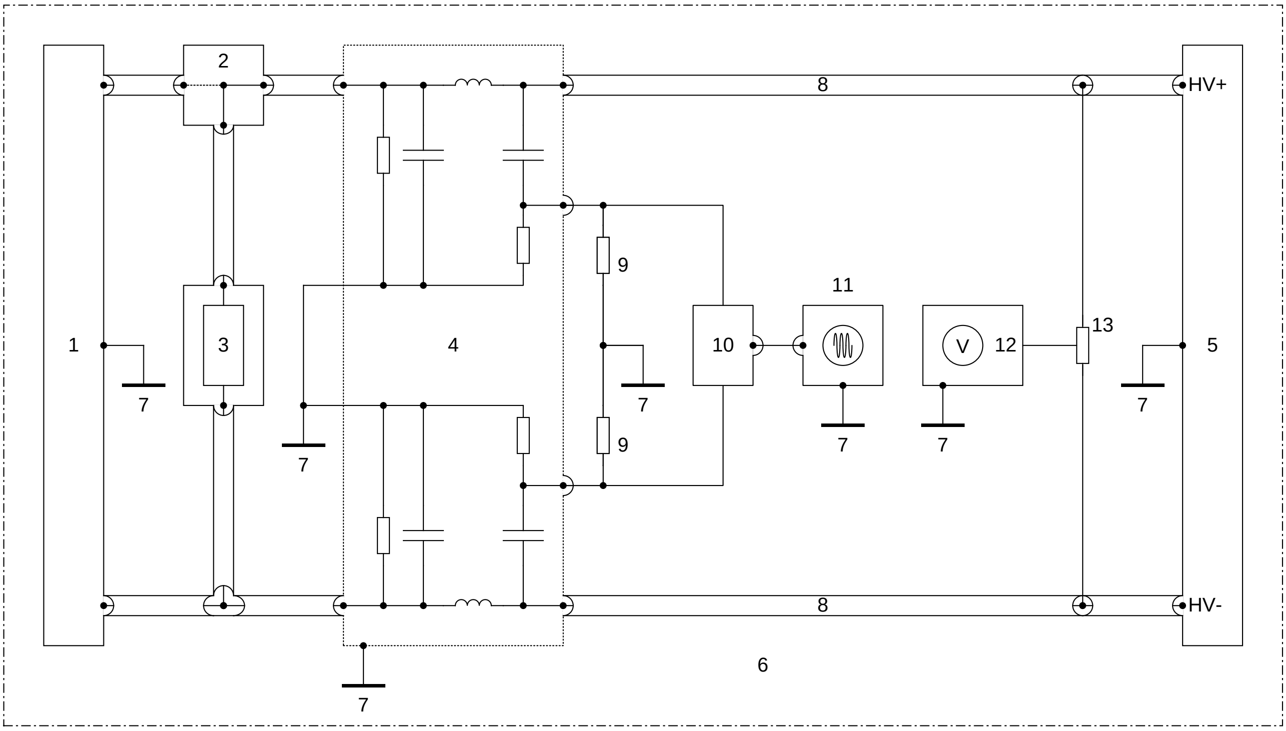
Figure 2b – Transient immunity test set-up for voltage ripple (e. g. “HV+ line-to-ground”)

Figure 2a shows the test setup for coupling between HV+ and HV-. For coupling between HV+ and ground or HV- and ground the bottom terminal of generator has to be connected to ground. The top terminal has to be connected to HV+ (as shown) or to HV-. Corresponding one voltage probe terminal has to be connected to HV+ respectively to HV-; the other voltage probe terminal has to be connected to ground.

Ground connection of DUT shall be connected to Ground plane with a cable original length and diameter according to the vehicle application.
Details to ground connection and wiring shall be agreed between vehicle manufacturer and supplier.

For square wave generator description/characteristics see 5.5.1.

4.4.2 Pulsed sinusoidal disturbances

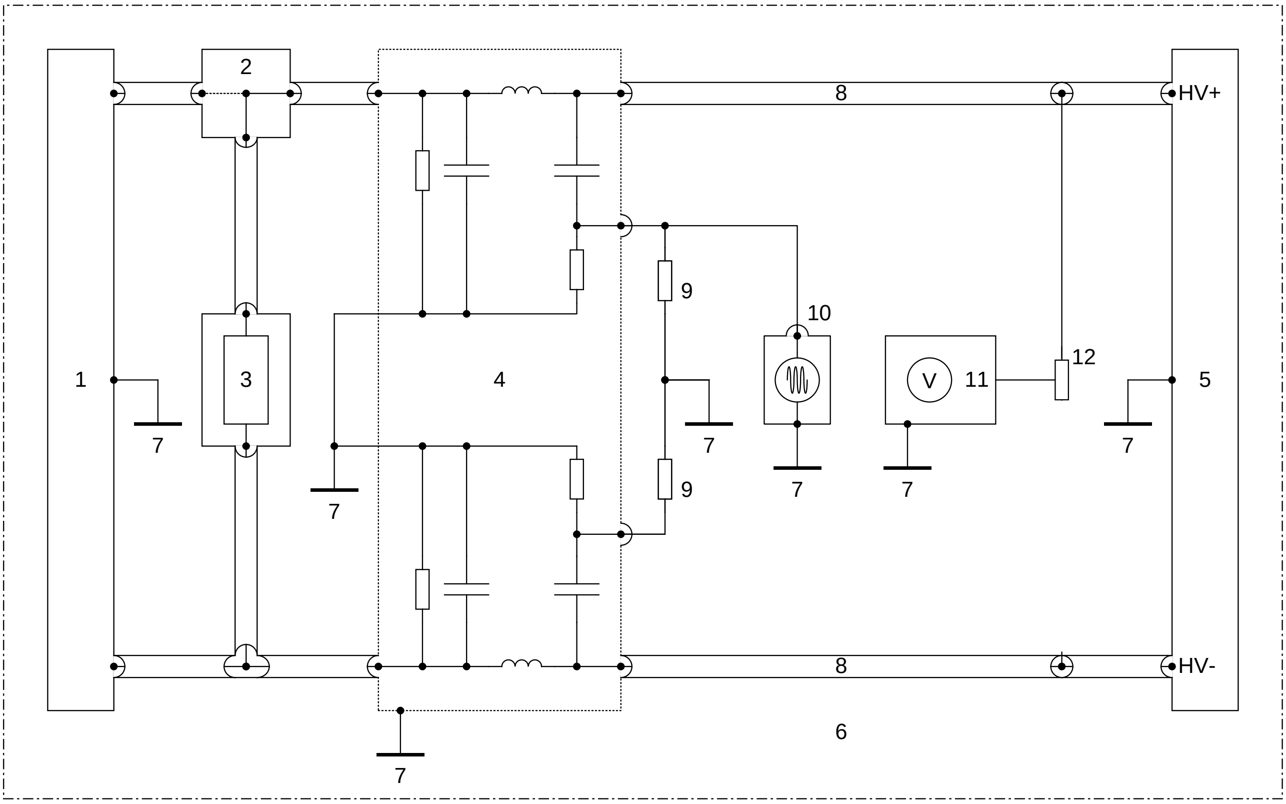


Key

1 shielded high voltage power supply
2 HV-Switch
3 load for high voltage battery (if necessary, see subclause 5.4)
4 shielded high voltage artificial network
5 DUT
6 ground plane
7 ground connection
8 High voltage supply line *)
9 50 Ohms termination
10 balun transformer
11 sine wave generator
12 oscilloscope or equivalent
13 high voltage differential probe

Figure 3a – Transient immunity test set-up for pulsed sinusoidal disturbances (e. g. “line-to-line”)

*) Length of the HV-cable depends from the routing in the vehicle, recommended sizes 200 mm (+200/-0 mm) or 1.700 mm + 300/ -0 mm (standard length) or length of the original HV-harness. The harness length has to be documented in the test plan.



Key

1 shielded high voltage power supply
2 HV-Switch
3 load for high voltage battery (if necessary, see subclause 5.4)
4 shielded high voltage artificial network
5 DUT
6 ground plane
7 ground connection
8 high voltage supply line *)
9 50 Ohms termination
10 sine wave generator
11 oscilloscope or equivalent
12 high voltage probe

Figure 3b – Transient immunity test set-up for pulsed sinusoidal disturbances (e. g. "HV+ line-to-ground")

Figure 3a shows the test setup for coupling between HV+ and HV-. For coupling between HV+ and ground or HV- and ground the bottom terminal of generator has to be connected to ground. The top terminal has to be connected to HV+ (as shown) or to HV-. Corresponding one voltage probe terminal has to be connected to HV+ respectively to HV-; the other voltage probe terminal has to be connected to ground.
Ground connection of DUT shall be connected to Ground plane with a cable original length and diameter according to the vehicle application.
Details to ground connection and wiring shall be agreed between vehicle manufacturer and supplier.
For sine wave generator description/characteristics see 5.5.2.

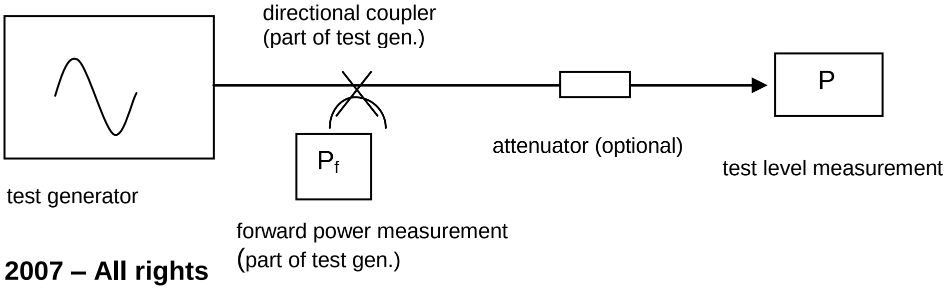


Figure 3c – Test setup for level setting

4.4.2.1 Level setting procedure (line to ground)

1. Set pulse frequency

Connect a power meter to the output of the test generator (see Fig. 3c);

NOTE An attenuator may be needed to protect the power meter input.

2. Record the forward power to obtain the desired test level (without modulation) measured at the output of the test generator (see Table A.2.2);
3. Repeat step 1-3 for all pulse frequencies.

4.4.2.2 Level setting procedure (line to line)

1. Set pulse frequency;
2. Connect a power meter to the output of the test generator (see Fig. 3c);

NOTE An attenuator may be needed to protect the power meter input.

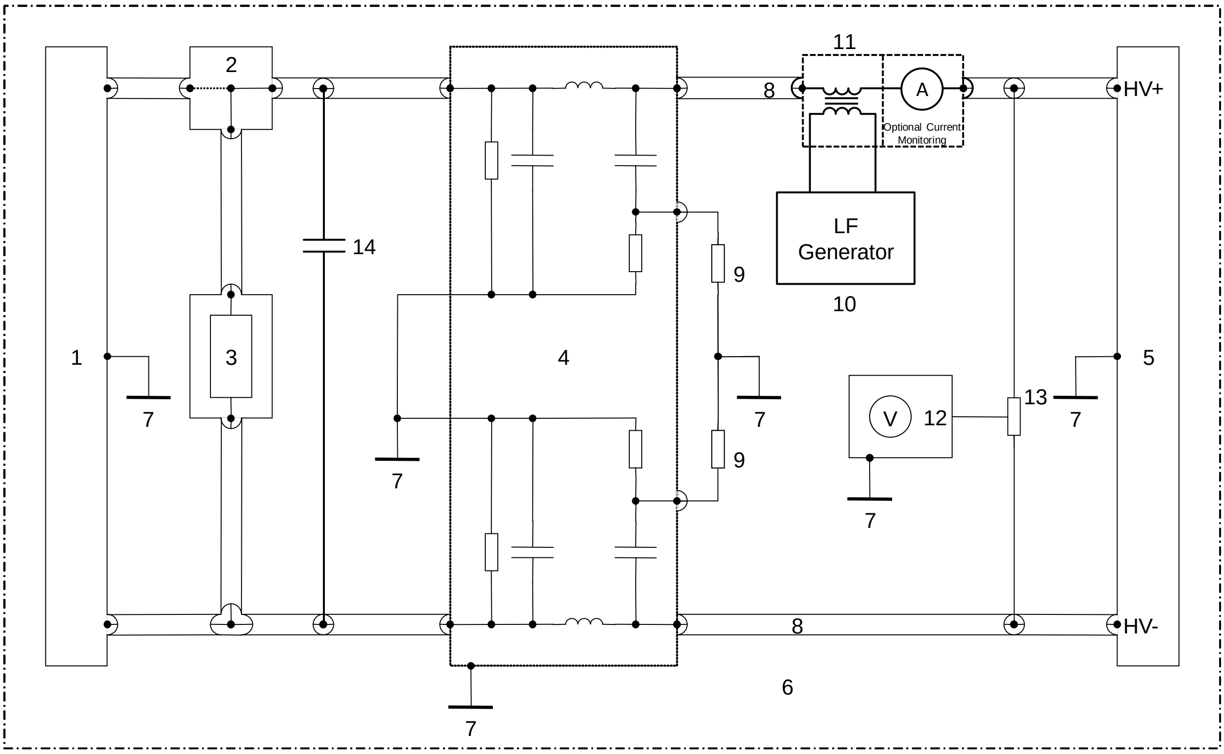
3. Record the forward power to obtain the desired test level (without modulation) measured at the output of the test generator (see Table A.2.2);
4. Correct the forward power by adding the correction factor of the balun transformer (see Fig. 3a, item 10) at the current pulse frequency;
5. Repeat step 1-4 for all pulse frequencies.

4.4.2.3 Execution of the test

The test shall be performed using the signal levels established during level setting process.

4.4.3 Low frequency sinusoidal disturbances

This test determines whether the equipment will accept superposed sinusoidal frequency components. This document provides the test procedure for testing frequency conducted susceptibility.

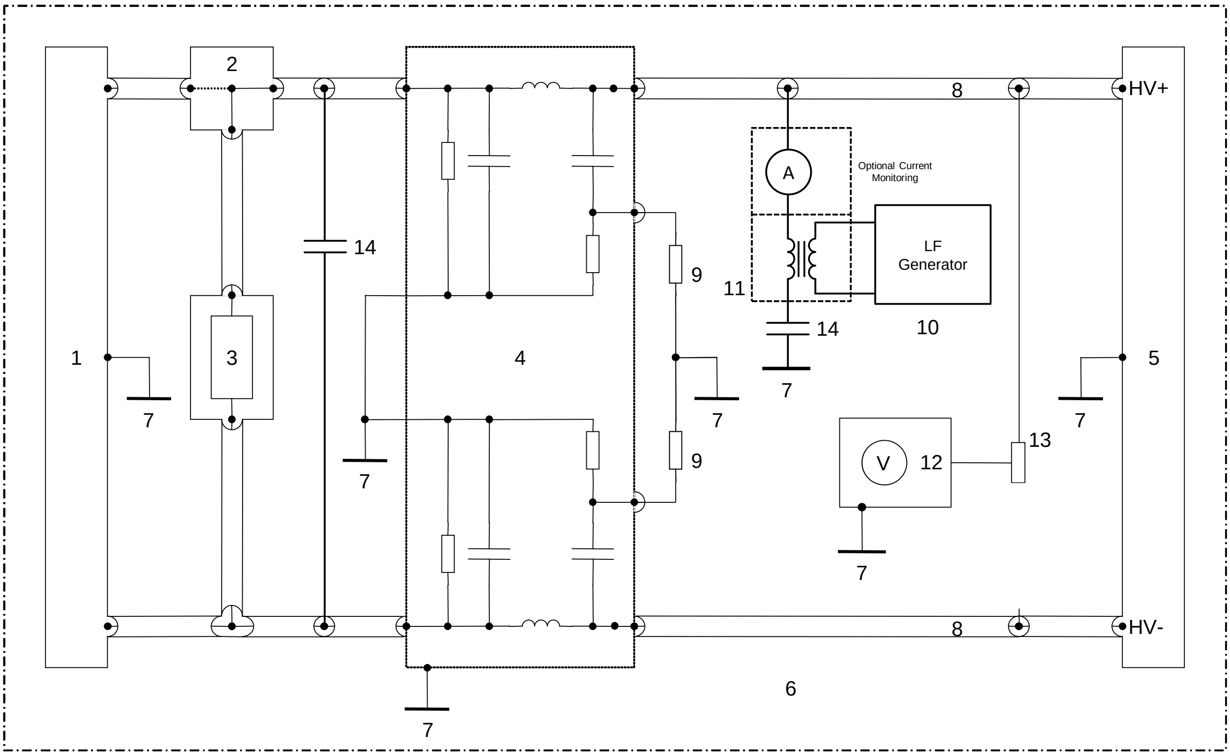


Key

1 shielded high voltage power supply
2 HV-Switch
3 load for high voltage battery (if necessary, see subclause 5.4)
4 shielded high voltage artificial network
5 DUT
6 ground plane
7 ground connection
8 high voltage supply line *)
9 50 Ohms termination
10 LF Generator
11 coupling transformer
12 oscilloscope or equivalent
13 high voltage differential probe
14 capacitor >100uF if using high voltage power supply instead a battery

Figure 4a – Transient immunity test set-up for low frequency sinusoidal disturbances (e. g. “line-to-line”)

*) Length of the HV-cable depends from the routing in the vehicle, recommended sizes 200 mm +200/-0 mm or 1.700 mm + 300/ -0 mm (standard length) or length of the original HV-harness. The harness length has to be documented in the test plan.



Key

1	shielded high voltage power supply
2	HV-Switch
3	load for high voltage battery (if necessary, see subclause 5.4)
4	shielded high voltage artificial network
5	DUT
6	ground plane
7	ground connection
8	high voltage supply line *)
9	50 Ohms termination
10	LF Generator
11	coupling transformer
12	oscilloscope or equivalent
13	high voltage probe
14	capacitor >100uF if using high voltage power supply instead a battery

Figure 4b – Transient immunity test set-up for low frequency sinusoidal disturbances (e. g. “HV+ line-to-ground”)

Figure 4a shows the test setup for coupling between HV+ and HV-. For coupling between HV+ and ground or HV- and ground the bottom terminal of the coupling transformer has to be connected to ground via capacitor. The top terminal has to be connected to HV+ (as shown) or to HV-. Corresponding one voltage probe terminal has to be connected to HV+ respectively to HV-; the other voltage probe terminal has to be connected to ground.

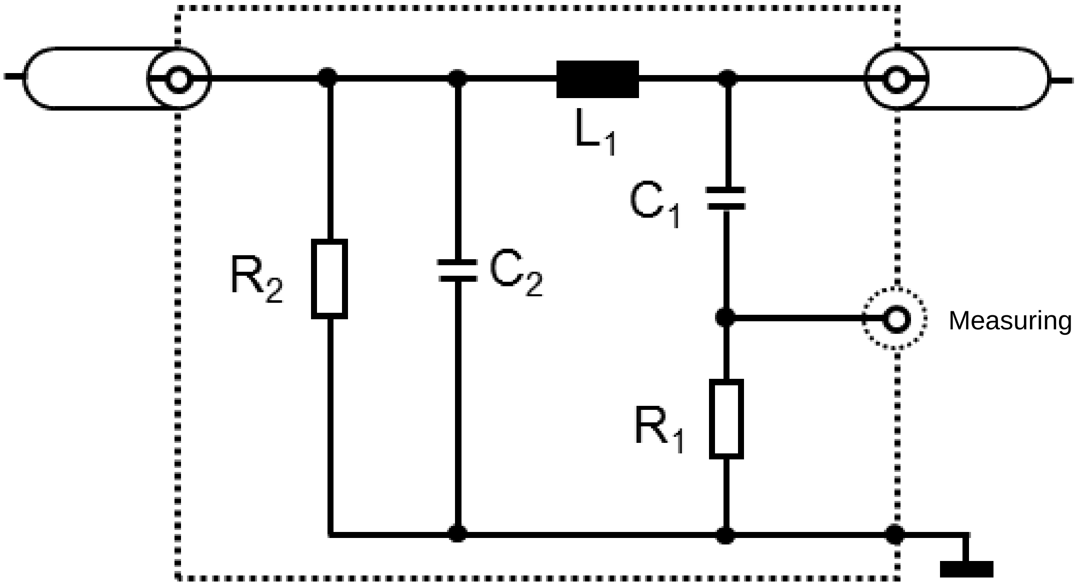
A capacitor of 100uF or more shall be connected across the high voltage dc power supply.
The optional current monitor is to measure the AC part of the frequency current and not the EUT current.
Ground connection of DUT shall be connected to Ground plane with a cable original length and diameter according to the vehicle application.
Details to ground connection and wiring shall be agreed between vehicle manufacturer and supplier.

For the LF sinusoidal generator and coupling transformer description/characteristics see 5.5.3.

5 Test instrument description and specifications

5.1 Shielded artificial network

The shielded high voltage artificial network (HV-LISN) is used as a reference standard in the laboratory in place of the impedance of the vehicle wiring harness in order to determine the behaviour of equipment and electrical and electronic devices. An example of a schematic diagram is given in figure 7.



Main characteristics of the circuit elements:

L_1:	5 µH	(air-core winding)
C_1:	0,1 µF	(1.000 V_{AC}, 2.000 V_{DC} , protected against direct contact “b”, self-curative)
C_2:	0,1 µF	(1.000 V_{AC}, 2.000 V_{DC} , protected against direct contact “b”, self-curative)
R_1:	1 kΩ	
R_2:	1 MΩ	(discharging of C_2 to voltages < 50 V_{DC} within less than 60 seconds)

Figure 5 – Schematic diagram of shielded artificial network

The shielded artificial network is different from the AN in CISPR 16. Both ANs, for HV+ and HV-, should be completely shielded in one enclosure. Shielding attenuation shall be min. 10 dB higher than the highest required shielding attenuation within the shielded HV system (DUT, wiring harness, power supply,…). All in- and outputs shall be designed that shielded cables or shielded connectors can be properly connected with the required low impedance.

The artificial network shall be able to withstand a continuous load corresponding to the requirements of the device under test.

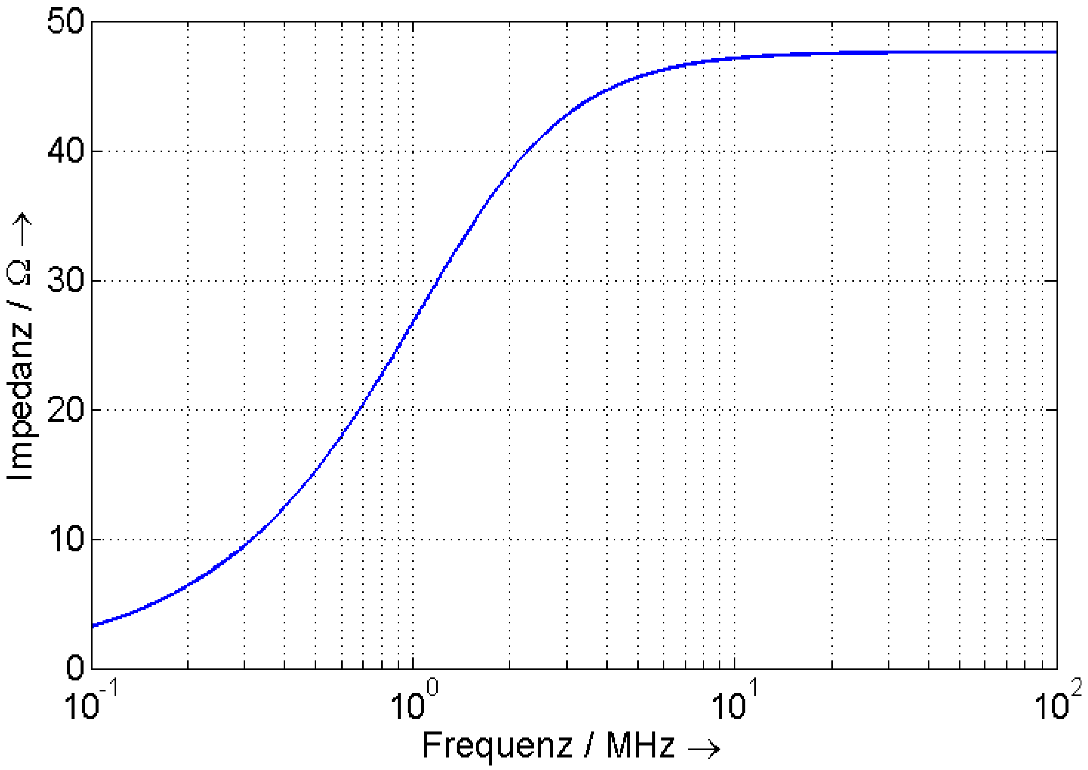


Figure 6 – Impedance of artificial network (AN)

The shielded artificial network shall be placed flat on the ground plane and the ground terminal on the power source and shall be connected to the ground plane.

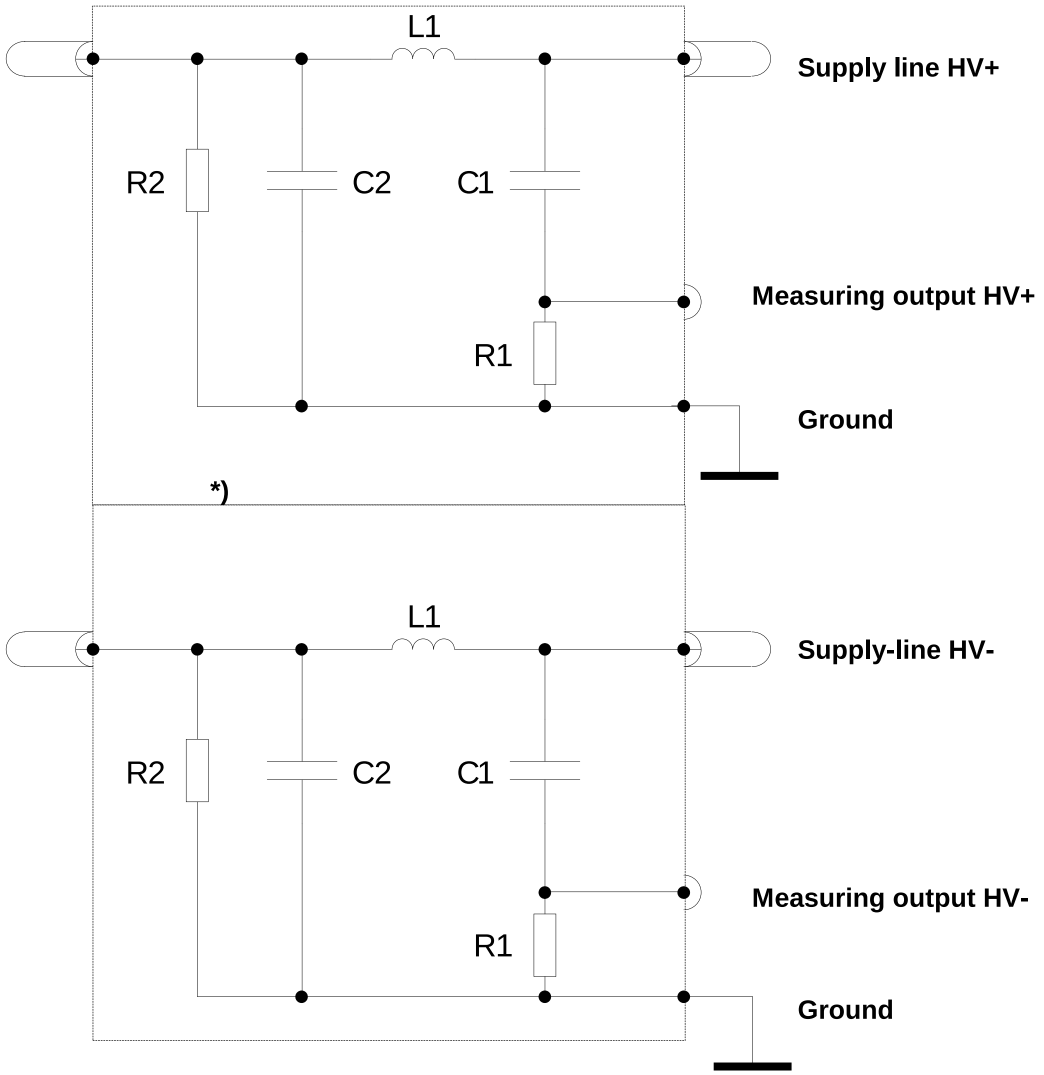


Figure 7 - Combination of shielded artificial networks (AN)

*) If unshielded AN's are housed in a single shielded box an inner shield between the two AN's is necessary.

5.2 Shielded high voltage power supply

The continuous source shall be able to supply the DUT with the necessary voltage range and supply current. Maximal noise ripple U_{pp} ≤ 1,5 % of nominal voltage.

5.3 Measurement instrumentation

As measuring equipment a digitizing oscilloscope or equivalent waveform acquisition equipment with voltage probes and the following parameters shall be used.

- Bandwidth DC to at least 400 MHz;
- Sampling rate: at least 2 Gigasamples per second (single shot mode).

Voltage measurement can be performed either with a differential probe or two matched common mode probes.

Differential mode probe characteristics:

Bandwidth DC to at least 100 MHz;

Input impedance Z ≥ 1 MΩ at DC.

Common mode probe, characteristics:

Bandwidth DC to at least 100 MHz;

Input impedance Z ≥ 1 MΩ at DC.

5.4 Load for high voltage battery

- Resistor 500 Ohms +/- 5 %

in parallel to

- Capacitor 10 µF +/- 10 %
  equivalent series resistance ESR < 5 mOhms at 10 kHz
  minimal current bearing capacity: 50 A_{rms} at 10 kHz
  (current bearing capacity shall be adapted to the test-voltage).

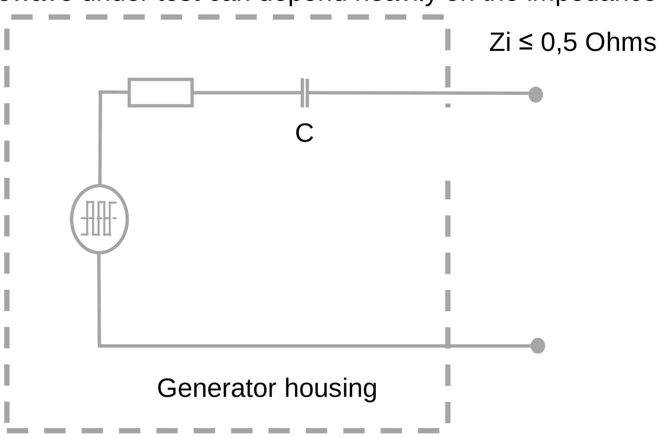
5.5 Test pulse generators for immunity testing

5.5.1 Test generator for Voltage Ripple, Pulse A

Generation of a continuous square-wave test-signal:

- Frequency range 1 kHz up to 300 kHz / 50 % duty-cycle;
- Frequency steps 1 kHz / 10 kHz;
- Zi Zi ≤ 0,5 Ohms (Zi = Upp / Ipp, measured at generator output (Figure 7) see Annex D2.1);
- T_{Rise}, T_{Fall} < 1 µs @ open circuit voltage (25 V_{pp});
- T_{Rise}, T_{Fall} < 2,5 µs @ short circuit current (> 30 A_{pp});
- Current capability ≥ 32 A (rms), ≥ 70 A (peak);
- Coupling capacitor For example: 120 µF +/- 10 %, protected against direct contact “b”, self-healing equivalent series resistance ESR < 5 mOhms @ 10 kHz minimal current bearing capacity: 50 A_{rms} @ 10 kHz
  (current bearing capacity shall be adapted to the test-voltage).
- Calibration parameters:
- Short circuit Current I_{SC} > 30 A_{pp} @ open circuit voltage V_{OC} = 25 $V_{pp;}$
- T_{rise}, T_{fall} < 1,0 µs at V_{OC} = 25 V_{pp} (1 kHz up to 300 kHz);
- T_{rise}, T_{fall} < 2,5 µs at I_{SC} > 30 A_{pp} (1 kHz up to 300 kHz);
- Z_i = V_{OC} / I_{SC} ≤ 0,8 ohms at 300 kHz.

Note: Shape of the squarewave under test can depend heavily on the impedance of the DUT.



Key

1 Zi = Total output impedance of generator for Voltage Ripple measured at output including coupling capacitor
2 C = Coupling capacitor (here implementation in the generator)

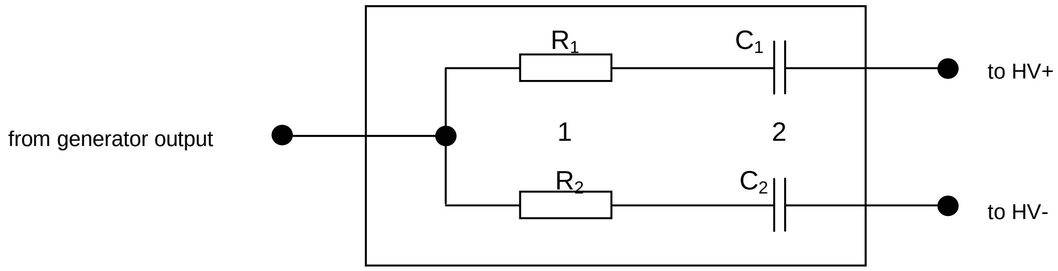
Figure 8 - Implementation of generator for Voltage Ripple

5.5.1.1 Coupling network for test on HV+ or/and HV- to ground

At given internal impedance of the voltage ripple generator the short circuit current is proportional to the required open circuit voltage. The internal components of a generator have a limited current capability. Therefore it can be necessary, to limit the output current for tests on HV+ to ground respectively on HV- to ground with an external resistor, because some DUTs contain capacitors with high capacity to ground.

Especially for tests on commercial vehicles where higher test levels for HV$\pm$ to ground (up to 250 V_{pp}), are required this external resistor for the generator is essential. For the recommended simultaneously HV+ to ground and HV- to ground test two coupling capacitors are necessary to avoid DC-current through the two external resistors. Figure 9 shows such a coupling network.

The test shall be performed in line-to-line- and in line-to-ground-mode. The simultaneous HV+ to ground and HV- to ground test (true common mode) requires a specfic coupling network that supplies the test pulses symmetrically to the two high voltage lines.



Key

1 1 R_1, R_2: > 10 Ohms (high power resistor; limiting of CM-current to protect the generator)
2 2 C_1, C_2: 30 µF (ESR < 5 mOhms @ 10 kHz)

Figure 9 - Coupling network for voltage ripple test (line(s)-to-ground)

5.5.2 Test generator for pulsed sinusoidal disturbances, Pulse B

The test generator shall have the following RF properties:

- frequency range: 1-10 MHz;
- impedance: 50 Ohm (nominal);
- output power for desired test level (example: Pout 25 W for 100 Vpp / 225 W for 300 Vpp).

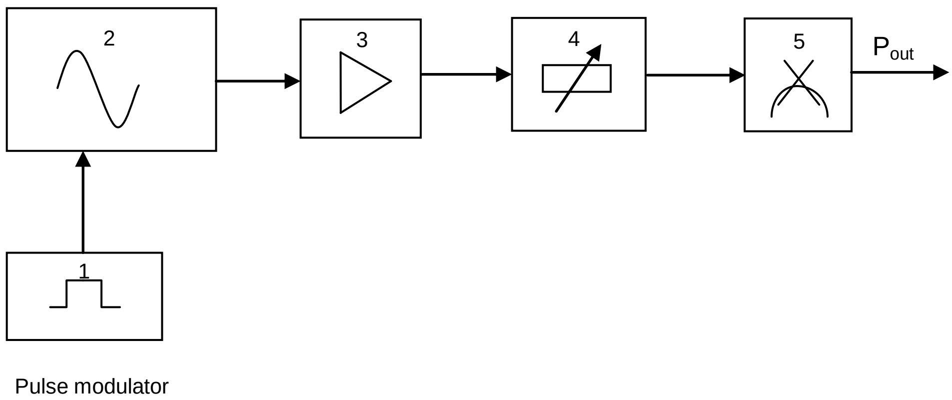


Figure 10 - Implementation of generator for pulsed sinusoidal disturbances

Key

1 pulse modulator
2 sine wave generator
3 RF-Amplifier
4 variable attenuator
5 directional coupler and forward power measurement: Pout

5.5.3 Test generator for low frequency sinusoidal disturbances, Pulse C

- Generation of a continuous sinusoidal test-signal:
- Frequency range 15 Hz up to 400 kHz;
- Frequency steps If no linear or logarithmic sweep is available, the test equipment should be capable of generating several frequencies per decade (see table A.2.2). The pulse duration at each frequency shall be at least 2s;
- Voltage capability 15 Hz up to 250 kHz: 30 V (rms);
  250 kHz up to 400 kHz: 20 V (rms);
- Current capability 16 A (rms).

If the induced current required to generate the specific signal voltage level is too high, the test conditions will be satisfied if the peak to peak current is limited to at least 20 amps. This peak to peak current is in addition to the normal DUT current from the high voltage dc power supply.

5.5.3.1 Coupling network for test on HV+ or/and HV- to ground

The coupling transformer is used to couple the required disturbances into the DUT. This transformer also facilitates DC isolation of the LF generator from the DUT. The transformer should be able to handle LF Power frequencies from 15 Hz to 400 kHz

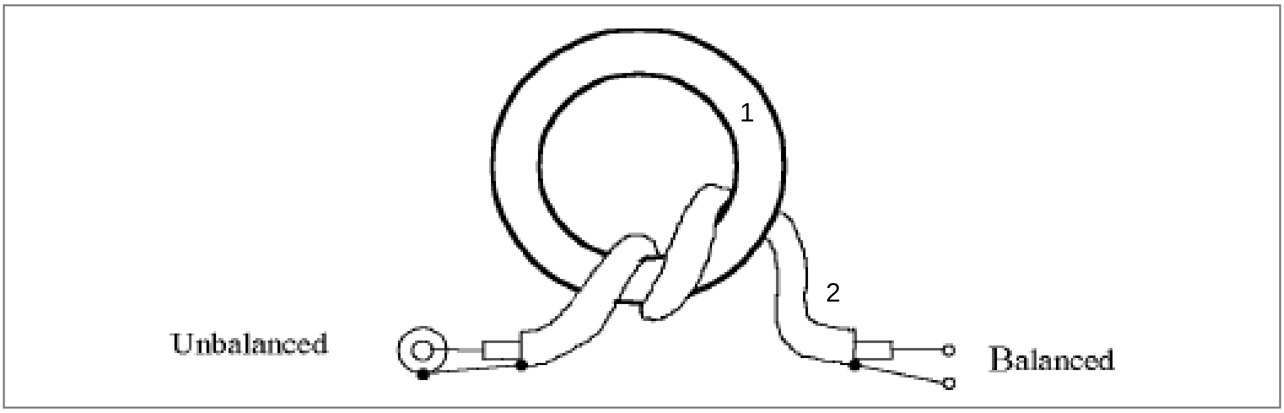
The test shall be performed in line-to-line- and in line-to-ground-mode.

For the LF sinusoidal generator and coupling transformer description/characteristics see 5.5.3.

5.5.3.2 Coupling Balun for line-to-line-coupling (sheath current filter)

For immunity testing against line-to-line coupled fast transients a balun as described in ANSI C37.90.1 – annex C – or equivalent may be used.

A simple transmission line transformer providing the unbalanced to balanced mode transformation is shown in Figure 11. Both terminals on the balanced side have to be terminated with 50 Ω to ground.



Key

1 ferrite core toroids (2 pieces, stacked up) A_L = 5400 nH/turn^2, 2x A_{LX} 256 = appr. 2,75 mH) inner diameter 39 mm, outer diameter 60 mm, core thickness 2x 18 mm

2 16 turns of 50 Ω coaxial cable with solid dielectric wound on the 2 stacked up toroids

Figure 11 - unbalanced / balanced transmission line transformer example

Annex A
(normative)

Example of test severity levels associated with functional performance status classification

A.1 General

This annex gives examples of test severity levels which should be used in line with the principle of functional performance status classification (FPSC) described in ISO 7637-1.

A.2 Classification of high voltage test pulse severity level

The suggested minimum and maximum severity levels for high voltage systems are given in tables A.2.1, A.2.2 and A.2.3.

A selected level and test time for testing at or in between these values may be chosen according to the agreement between vehicle manufacturer and supplier. In cases where no specific values are defined, it is recommended to use levels from tables A.2.1, A.2.2 and A.2.3.

A.2.1

A.2.1 Test pulse A, Voltage Ripple

Table A.2.1 – Parameters for test pulse A, voltage ripple

Test frequency f_{PWM}	Frequency step	Test voltage U_{pp} [V] *) severity level				Dwell time per step (s)	Test coupling
		I	II	III	IV		
3 kHz - 30 kHz	1 kHz	5	25	50	**)	2	HV+ to HV- HV+ to ground HV- to ground optional: HV+ and HV-to ground
30 kHz – 300 kHz	10 kHz	0,5	2,5	5	**)		

*) Test voltage shall be aligned without load.

****)** Severity level class for special applications: Details shall be agreed between vehicle manufacturer and supplier

The frequency ranges may be changed to 1 kHz – 20 kHz and 20 kHz – 300 kHz. Since many inverters use 4-12 kHz switching frequency. Details shall be agreed between vehicle manufacturer and supplier.

A.2.2 Test pulse B, Pulsed Sinusoidal Disturbances

Table A.2.2 – Parameters for test pulse B, pulsed sinusoidal disturbances

Pulse	Test voltage U_{pp} [V] *)	Oscillations	Repetition	Test	Test

frequency (MHz)	severity level				per pulse packet	time (µs)	duration (minutes)	coupling
	I	II	III	IV				
1	20	50	100	**)	10	200 / 100 / 50	5 / 5 / 5	HV+ to HV- HV+ to ground HV- to ground
2								
5								
10								

*) Test voltage shall be aligned at 50 ohm load. The load remains in the test setup Details shall be agreed between vehicle manufacturer and supplier.

****)** Severity level class for special applications: Details shall be agreed between vehicle manufacturer and supplier

A.2.3 Test pulse C, Low Frequency Sinusoidal disturbances

Table A.2.3 – Parameters for test pulse C, Low Frequency Sinusoidal disturbances

Test frequency f_{PWM}	Frequency step	Test voltage U_{pp} [V] severity level				Dwell time per step (s)	Test coupling
		I	II	III	IV		
Optional: < 3 kHz *)	*)	*)	*)	*)	**)	2	HV+ to HV- HV+ to ground HV- to ground
3 kHz - 30 kHz	f.e. 1 kHz	5	15	25	**)		
30 kHz - 300 kHz	f.e. 10 kHz	0,5	1,5	2,5	**)		
Optional: > 300 kHz ***)	***)	***)	***)	***)	***)		

*) Optional test frequencies and severity levels for applications with relevant harmonics < 3 kHz: Details shall be agreed between vehicle manufacturer and supplier

****)** Severity level class for special applications: Details shall be agreed between vehicle manufacturer and supplier

***) Test frequencies and severity levels for applications with relevant harmonics > 300 kHz: Details shall be agreed between vehicle manufacturer and supplier

A.3 Example of FPSC application, using test pulse severity Levels

An example of severity levels is given in table A.3.1. This table can be different for each kind of pulse, and for different high voltage electrical vehicle systems (levels from table A.2.1 to A.2.3).

Table A.3.1- Example of FPSC Levels

	Category 1	**Category 2**	**Category 3**
L_{4i}	Level IV	Level IV	Level IV
L_{3i}	Level III	Level IV	Level IV
L_{2i}	Level III	Level III	Level IV
L_{1i}	Level III	Level III	Level III

Annex B
(normative)

Transient voltage waveform evaluation

B.1 General

The purpose of this annex is to provide a method of evaluation to characterise transient emissions from disturbance sources as tested according to the test conditions specified in 3 of the main part of this standard.

B.2 Essential elements of transient emission waveform characteristics

The following waveform parameters are to be taken into consideration for the evaluation of waveform characteristics (see ISO 7637 part 1 for definitions).

Abbreviations have been assigned to the waveform parameters as given in Table B.1

Table B.2.1 - Terms and abbreviations

Parameter	Definition see part 1, clause	Abbreviation
Peak amplitude	3.12	U_s (U_{S1}, U_{S2})
Pulse duration	3.13.1	t_d
Pulse rise time	3.13.2	t_r
Pulse fall time	3.13.3	t_f
Pulse repetition time	3.14.4	t_1
Burst duration	3.14.1	t_4
Time between bursts	3.14.2	t_5
Burst cycle time	3.14.3	$t_4 + t_5$

B Voltage waveform characteristics and classification of transient emissions

B.3.1 Test pulse A, Voltage Ripple

T_{rise} < 1µs T_{fall} < 1 µs

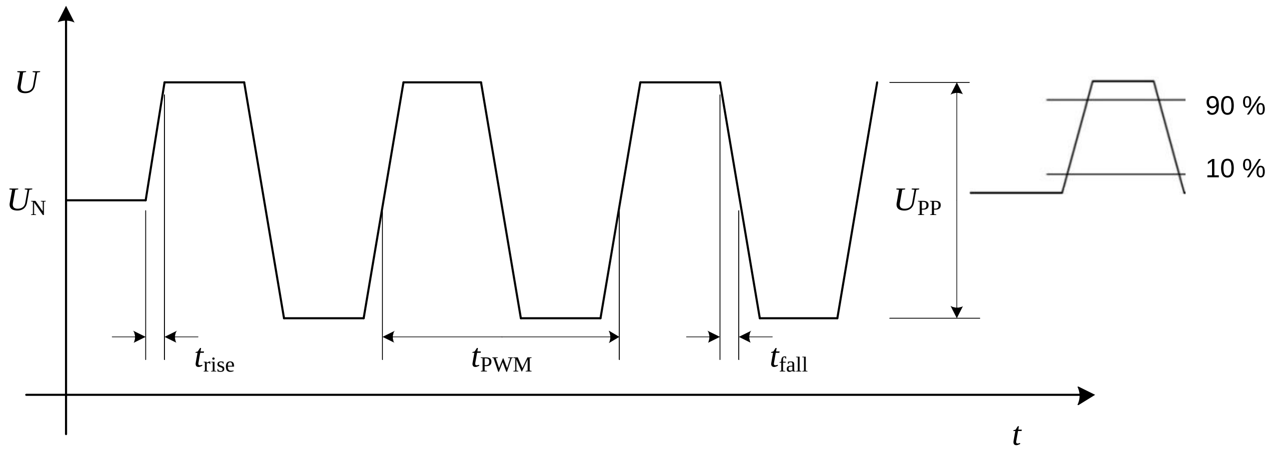


Figure B.3.1: Test pulse A, Voltage Ripple

Test pulses shall be adjusted without load and without DUT.

B.3.2 Test pulse B, Pulsed Sinusoidal Disturbances

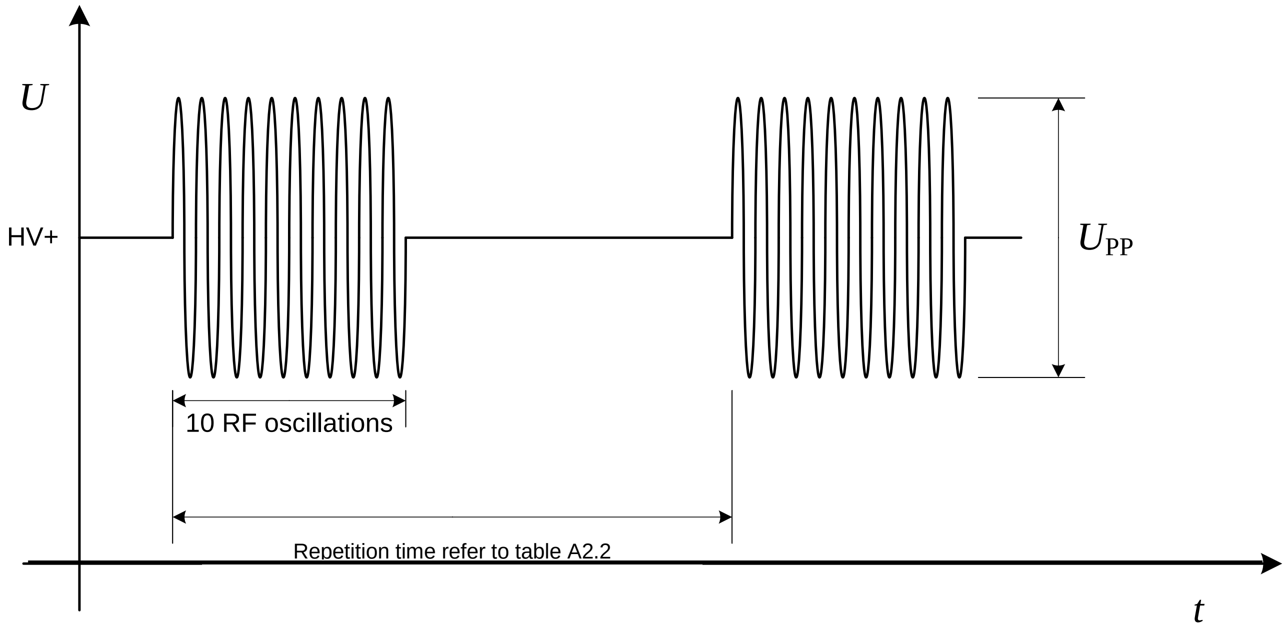


Figure B.3.2 - Test pulse B, sine wave pulses, e. g. on HV+

Test B shall be adjusted with 50 Ohm termination at transmitter output.

B.3.3 Test pulse C, Low Frequency Sinusoidal Disturbances

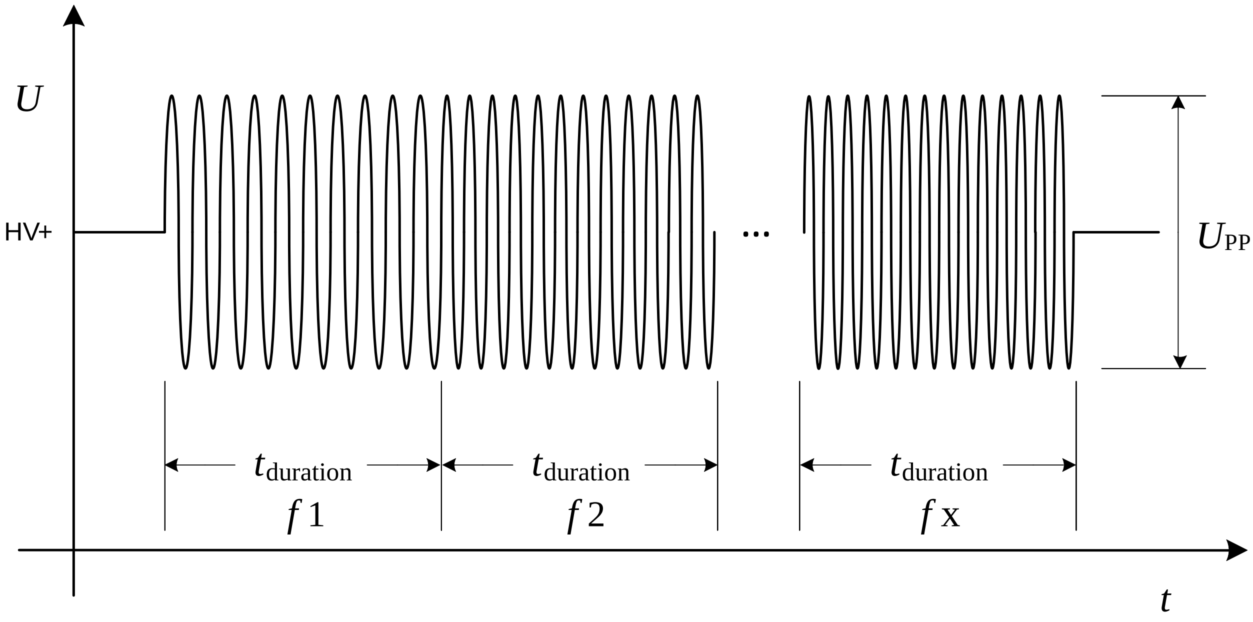


Figure B.3.3 - Test pulse C, Low Frequency Sinusoidal Disturbances

Annex C
(informative)

Test pulse generator verification procedure

C.1 Scope

The purpose of this annex is to provide a method for the verification of the output characteristics of the test pulse generator.

C.2 Voltage ripple

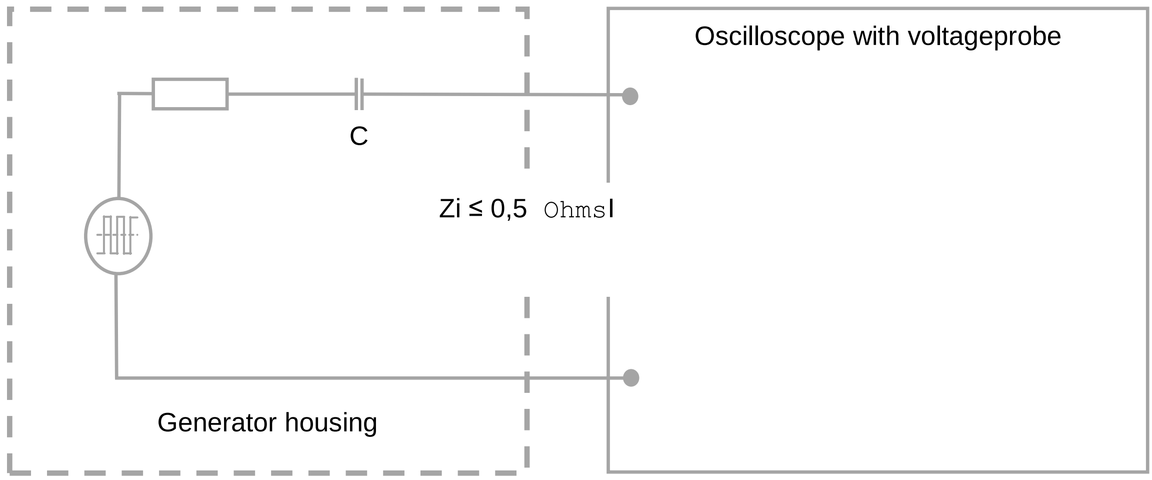
The verification measurements are performed under three different conditions to determine the behaviour of the test pulse generator:

— Under open condition;

— Under short condition;

— With LISN and Load.

Figure C.1 shows the verification setup for open condition. The output voltage of the generator is measured with an oscilloscope, which input is in high resistance setting. All transducers have to be considered and results have to be cleared from transducers.

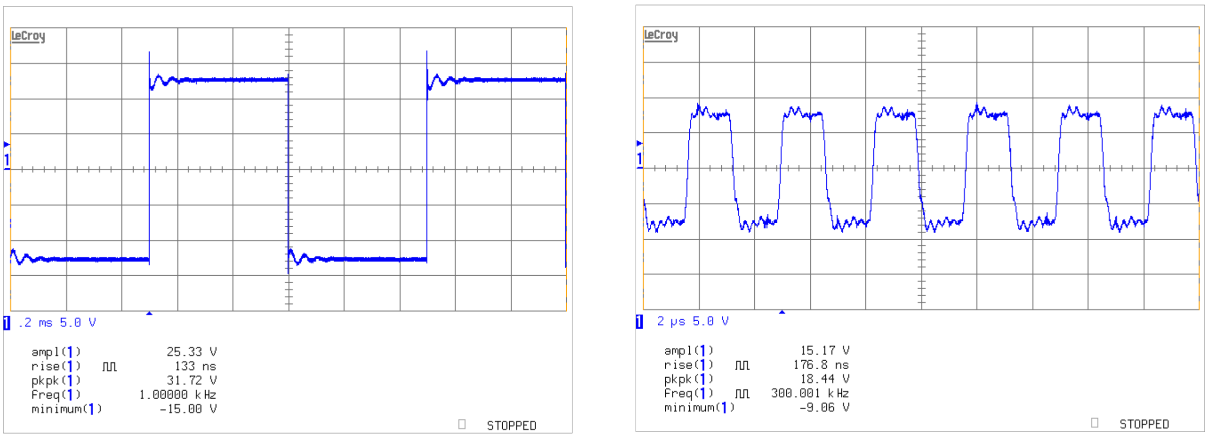


Key

1 Zi = Total inner impedance of generator for Voltage Ripple (including coupling capacitor)
2 C = Coupling capacitor (here implementation in the generator)

Figure C.1 Pulse verification under open condition

For information: Figure C.2 shows some example voltage pulses recorded with the open setup.

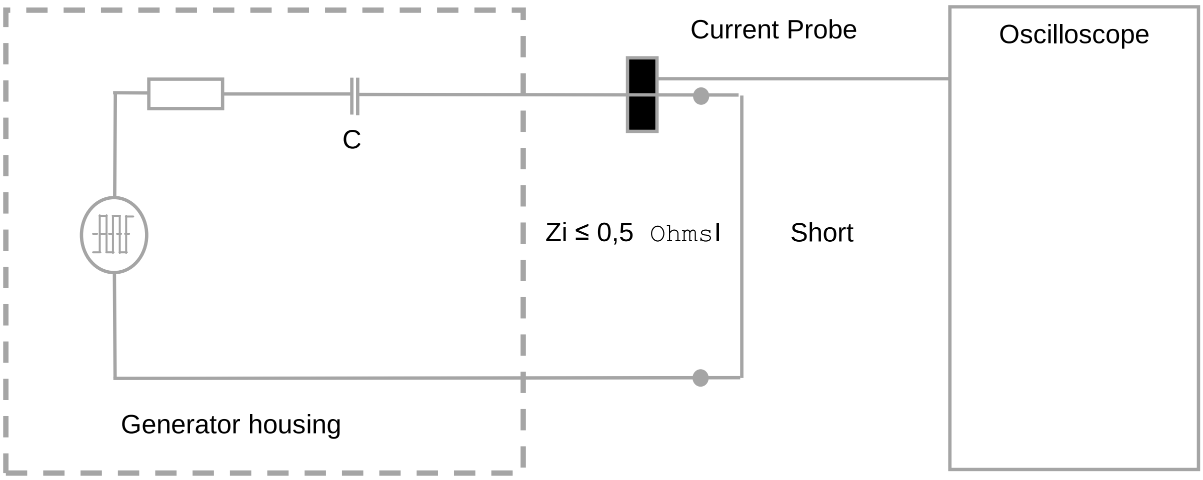


Key

1 Left: Pulse repetition = 1 kHz, Vpp = 25 V
2 Right: Pulse repetition = 300 kHz, Vpp = 18,44 V, Vin = 15 Vpp

Figure C.2 Example pulses: Open condition

Figure C.3 shows the verification setup for short condition. In this measurement a current probe and an oscilloscope is used to verify the current behaviour of the generator. All transducers have to be considered, especially from the current probe and results have to be cleared from transducers.

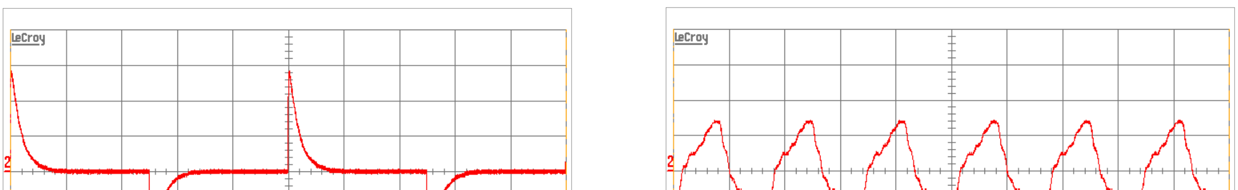


Key

1 Zi = Total inner impedance of generator for Voltage Ripple (including coupling capacitor)
2 C = Coupling capacitor (here implementation in the generator)

Figure C.3 Pulse verification under short condition

For information: Figure C.4 shows some example current pulses recorded with the short setup.



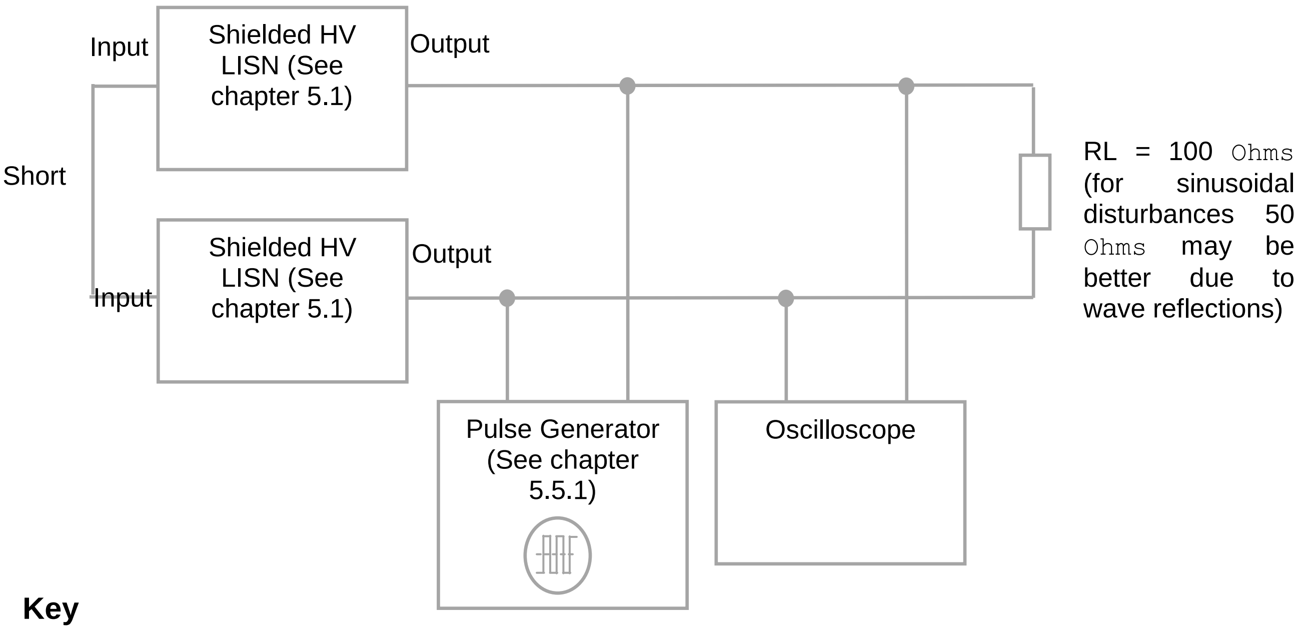
Key

1 Left: Pulse repetition = 1 kHz, Ipp > 130 A, Vin = 25 Vpp, Zi < 0.36 Ohms (Figure only for timebase verification)

2 Right: Pulse repetition = 300 kHz, Ipp > 29 A, Vin = 25 Vpp, Zi < 0.53 Ohms (Figure only for timebase verification)

Figure C.4 Example pulses: Short condition (only for time base evaluation)

In order to find a better agreement with the vehicle, pulse verification with LISN is recommended. The setup is shown in Figure C.5. The vehicle harness is reproduced by two CISPR 25-LISN (see chapter 5.1).

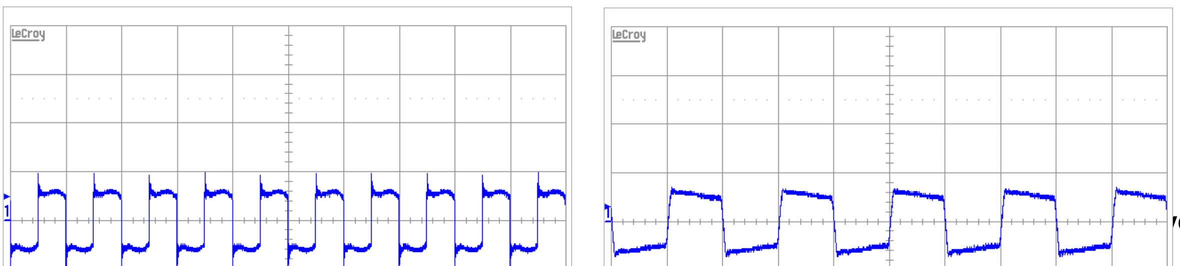


Key

1 RL = Load resistor (for ripple 100 Ohms and for sinusoidal disturbances 50 Ohms is recommended)

Figure C.5 - Pulse verification with LISN and load

For information: Figure C.6 shows some example pulses recorded with the LISN and load setup.



Key

1 Left: Pulse repetition = 20 kHz, Vin = 25 Vpp
2 Right: Pulse repetition = 100 kHz, Vin = 25 Vpp

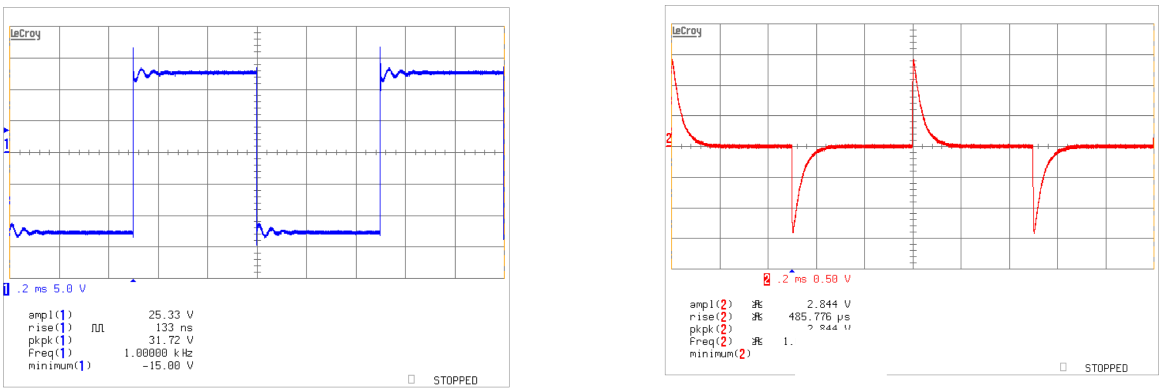
Figure C.6 - Example pulses: LISN and load condition (only for time base evaluation)

C.2.1 Determination of Zi in timebase

In order to determine the relevant Zi it is recommended to use the open and short setup to determine Upp and Ipp (Peak-to-Peak) with the same input voltage Vin. The coupling capacitor should be included in these measurements to derive most significant results. Zi can be calculated by Zi = Vpp/Ipp in which all transducers have been considered and the measurement data is cleared from them.

The important electromagnetic disturbances especially occur in the rising or falling slope of the voltage pulses, where the amplitude reaches its maximum. If Zi is determined after the capacitor by using the Peak-Peak-values, most side effects are considered. In this case Zi is valid for the most threatening phase of the voltage pulses and therefore valid to specify the generator performance.

For information, in figure C.7 an example is given to determine Zi.



Key

1 Left: Pulse repetition = 1 kHz, Vpp = 31.72 V, Vin = 25 Vpp

2 Right: Pulse repetition = 1 kHz, Ipp > 130 A, Vin = 25 Vpp (Figure only for timebase verification)

Figure C.7 Example to determine Zi

Figure C.7 shows Vpp = 25 V and Ipp > 130 A. Therefore Zi = (25 V/65 A) = 0,38 Ohms.

C.3 Pulsed sinusoidal disturbances

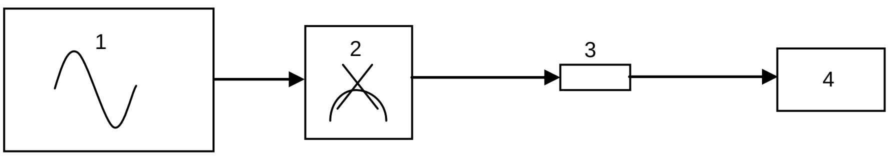


Figure C.8 Pulse verification setup for pulsed sinusoidal disturbances

Key

1 test generator
2 directional coupler and forward power measurement: P_{out}
3 variable attenuator (optional)
4 test level measurement